

2N7002KA

N-channel TrenchMOS FET

Rev. 02 — 25 September 2007

Product data sheet

1. Product profile

1.1 General description

N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology.

1.2 Features

- Logic level compatible
- Subminiature surface-mounted package
- Very fast switching
- Gate-source ESD protection diodes

1.3 Applications

- Relay driver
- High-speed line driver

1.4 Quick reference data

- $V_{DS} \leq 60 \text{ V}$
- $R_{DSon} \leq 4.4 \ \Omega$
- $I_D \leq 300 \text{ mA}$
- $P_{tot} \leq 0.83 \text{ W}$

2. Pinning information

Table 1. Pinning

Pin	Description	Simplified outline	Symbol
1	gate (G)	<p>SOT23 (TO-236AB)</p>	<p>003aac036</p>
2	source (S)		
3	drain (D)		

3. Ordering information

Table 2. Ordering information

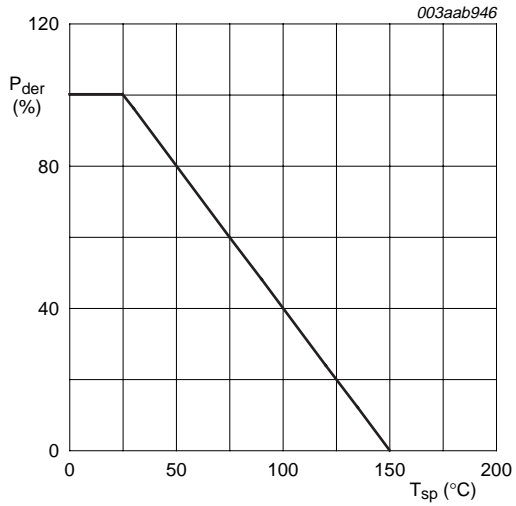
Type number	Package		Version
	Name	Description	
2N7002KA	TO-236AB	plastic surface-mounted package; 3 leads	SOT23

4. Limiting values

Table 3. Limiting values

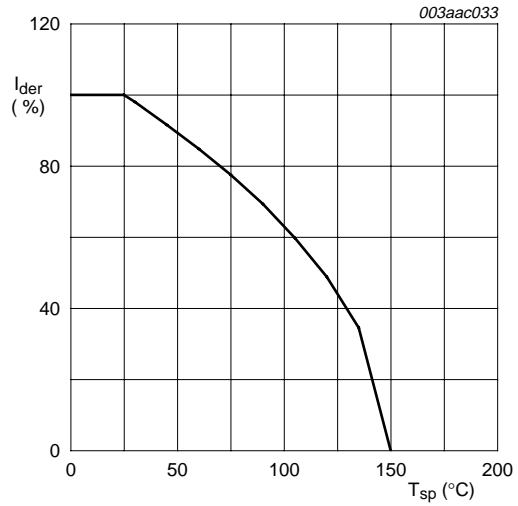
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$25\text{ °C} \leq T_j \leq 150\text{ °C}$	-	60	V
V_{DGR}	drain-gate voltage (DC)	$25\text{ °C} \leq T_j \leq 150\text{ °C}$; $R_{GS} = 20\text{ k}\Omega$	-	60	V
V_{GS}	gate-source voltage		-	± 15	V
V_{GSM}	peak gate-source voltage	$t_p \leq 50\text{ }\mu\text{s}$; pulsed; duty cycle = 25 %	-	± 40	V
I_D	drain current	$T_{sp} = 25\text{ °C}$; $V_{GS} = 10\text{ V}$; see Figure 2 and 3	-	320	mA
		$T_{sp} = 100\text{ °C}$; $V_{GS} = 10\text{ V}$; see Figure 2	-	200	mA
I_{DM}	peak drain current	$T_{sp} = 25\text{ °C}$; pulsed; $t_p \leq 10\text{ }\mu\text{s}$; see Figure 3	-	1.28	A
P_{tot}	total power dissipation	$T_{sp} = 25\text{ °C}$; see Figure 1	-	0.83	W
T_{stg}	storage temperature		-55	+150	°C
T_j	junction temperature		-55	+150	°C
Source-drain diode					
I_S	source current	$T_{sp} = 25\text{ °C}$	-	300	mA
I_{SM}	peak source current	$T_{sp} = 25\text{ °C}$; pulsed; $t_p \leq 10\text{ }\mu\text{s}$	-	1.2	A



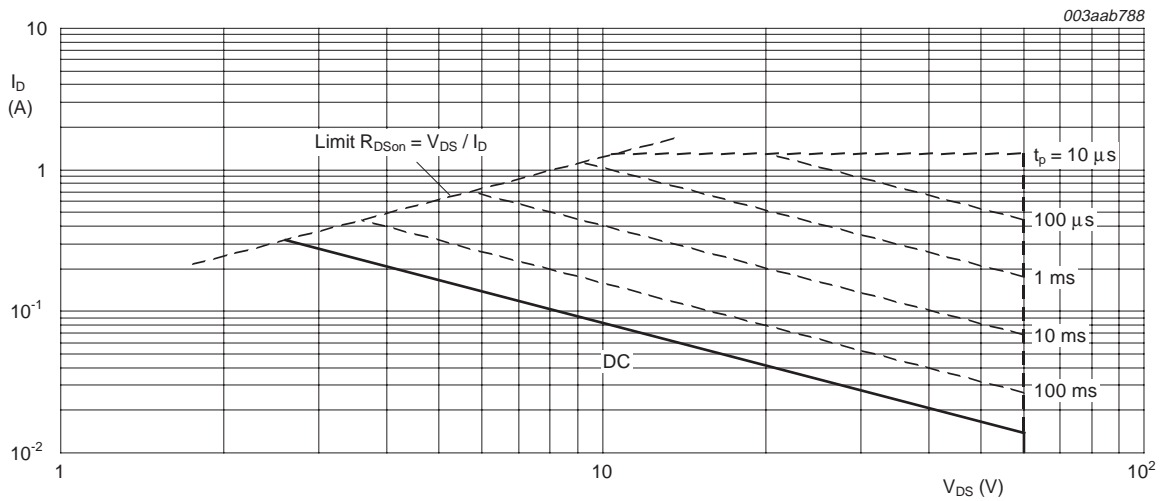
$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

Fig 1. Normalized total power dissipation as a function of solder point temperature



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$

Fig 2. Normalized continuous drain current as a function of solder point temperature



T_{sp} = 25 °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	see Figure 4	-	-	150	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient		[1]	-	350	K/W

[1] Mounted on a printed-circuit board; minimum footprint; vertical in still air.

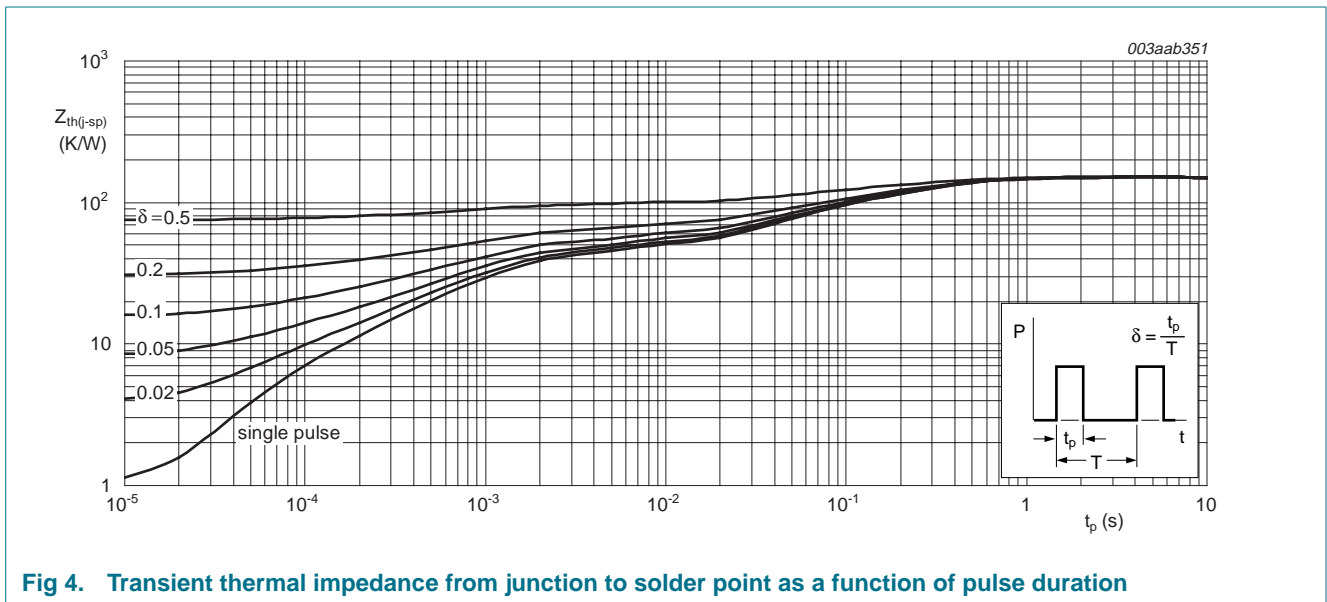


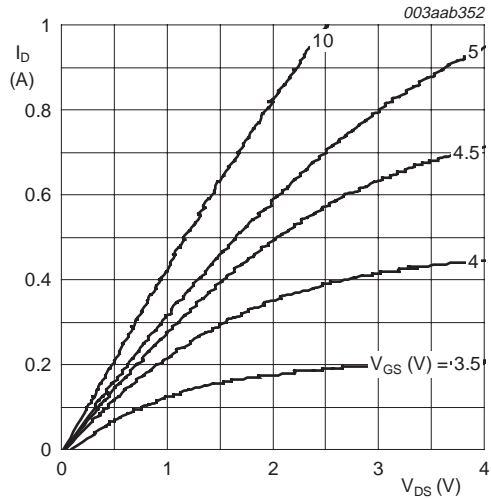
Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration

6. Characteristics

Table 5. Characteristics

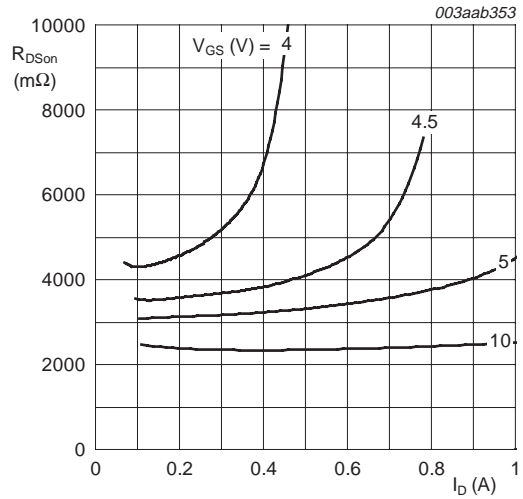
$T_j = 25\text{ °C}$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 10\ \mu\text{A}; V_{GS} = 0\ \text{V}$				
		$T_j = 25\text{ °C}$	60	75	-	V
		$T_j = -55\text{ °C}$	55	-	-	V
$V_{(BR)GSS}$	gate-source breakdown voltage	$I_G = \pm 1\ \text{mA}; V_{DS} = 0\ \text{V}$	16	22	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1\ \text{mA}; V_{DS} = V_{GS};$ see Figure 9 and 10				
		$T_j = 25\text{ °C}$	1	2	-	V
		$T_j = 150\text{ °C}$	0.6	-	-	V
		$T_j = -55\text{ °C}$	-	-	3.5	V
I_{DSS}	drain leakage current	$V_{DS} = 48\ \text{V}; V_{GS} = 0\ \text{V}$				
		$T_j = 25\text{ °C}$	-	0.01	1	μA
		$T_j = 150\text{ °C}$	-	-	10	μA
I_{GSS}	gate leakage current	$V_{GS} = \pm 10\ \text{V}; V_{DS} = 0\ \text{V}$	-	50	500	nA
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = 10\ \text{V}; I_D = 500\ \text{mA};$ see Figure 6 and 8				
		$T_j = 25\text{ °C}$	-	2.8	4.4	Ω
		$T_j = 150\text{ °C}$	-	-	8.14	Ω
		$V_{GS} = 4.5\ \text{V}; I_D = 75\ \text{mA};$ see Figure 6 and 8	-	3.8	5.3	Ω
Dynamic characteristics						
C_{iss}	input capacitance	$V_{GS} = 0\ \text{V}; V_{DS} = 10\ \text{V}; f = 1\ \text{MHz};$ see Figure 12	-	13	40	pF
C_{oss}	output capacitance		-	8	30	pF
C_{rss}	reverse transfer capacitance		-	4	10	pF
t_{on}	turn-on time	$V_{DS} = 50\ \text{V}; R_L = 250\ \Omega; V_{GS} = 10\ \text{V};$ $R_G = 50\ \Omega; R_{GS} = 50\ \Omega$	-	3	10	ns
t_{off}	turn-off time		-	9	15	ns
Source-drain diode						
V_{SD}	source-drain voltage	$I_S = 300\ \text{mA}; V_{GS} = 0\ \text{V};$ see Figure 11	-	0.85	1.5	V
t_{rr}	reverse recovery time	$I_S = 300\ \text{mA}; dI_S/dt = -100\ \text{A}/\mu\text{s}; V_{GS} = 0\ \text{V};$ $V_{DS} = 25\ \text{V}$	-	30	-	ns
Q_r	recovered charge		-	30	-	nC



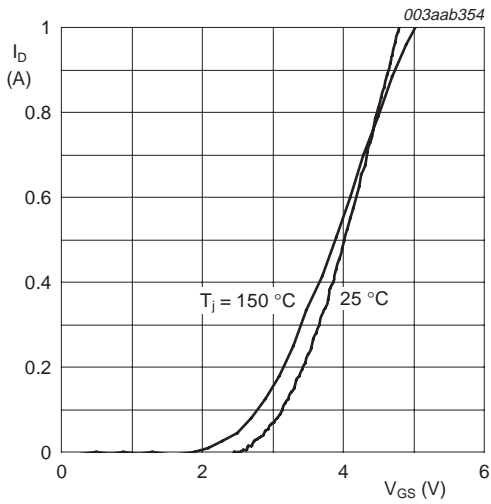
$T_j = 25\text{ }^\circ\text{C}$

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



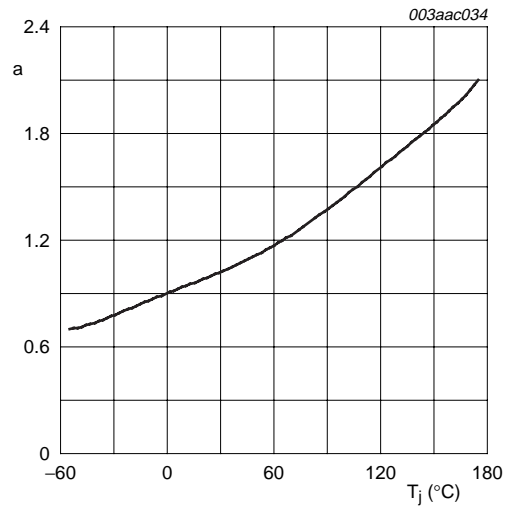
$T_j = 25\text{ }^\circ\text{C}$

Fig 6. Drain-source on-state resistance as a function of drain current; typical values



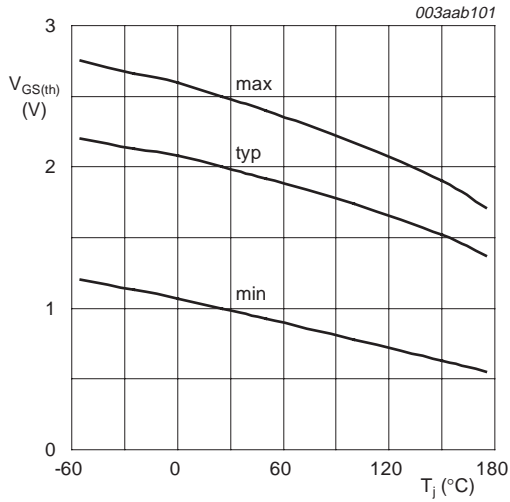
$T_j = 25\text{ }^\circ\text{C}$ and $150\text{ }^\circ\text{C}$; $V_{DS} > I_D \times R_{DSon}$

Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values



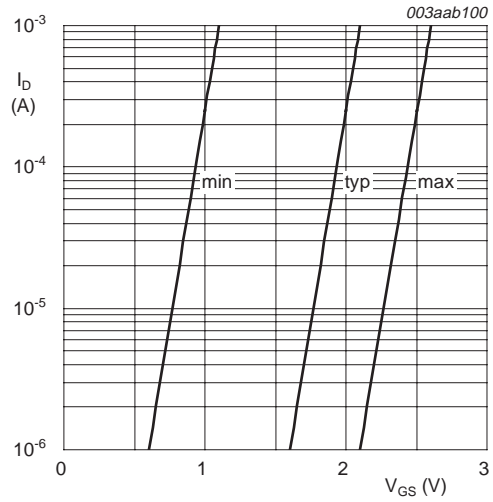
$$a = \frac{R_{DSon}}{R_{DSon(25^\circ\text{C})}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



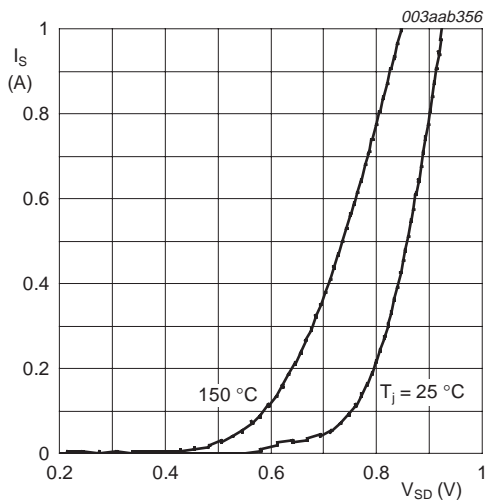
$I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



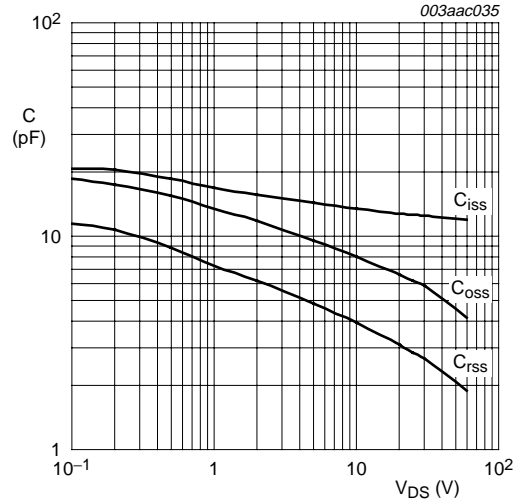
$T_j = 25 \text{ }^{\circ}C; V_{DS} = 5 \text{ V}$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



$T_j = 25 \text{ }^{\circ}C \text{ and } 150 \text{ }^{\circ}C; V_{GS} = 0 \text{ V}$

Fig 11. Source current as a function of source-drain voltage; typical values



$V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

7. Package outline

Plastic surface-mounted package; 3 leads

SOT23

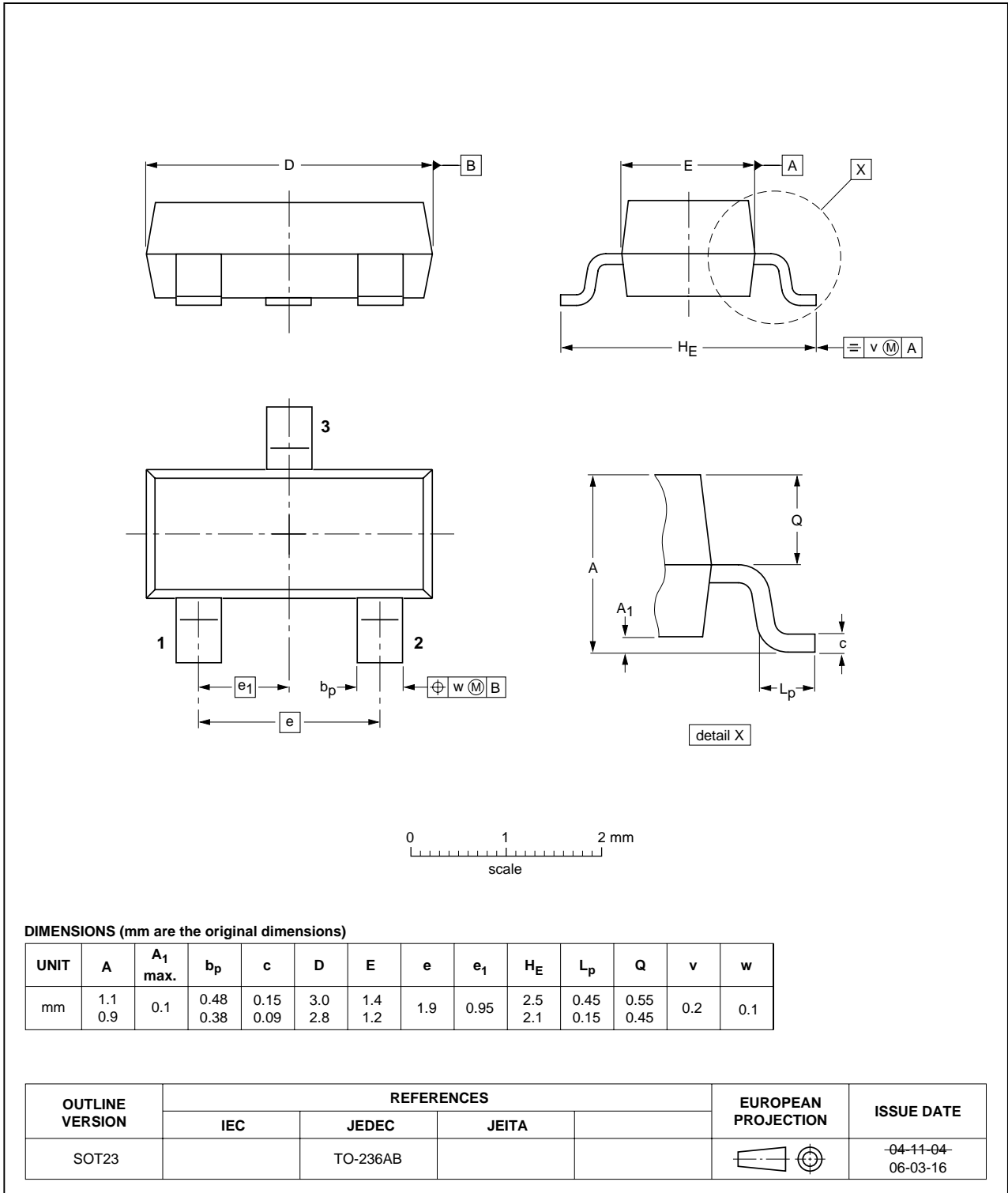


Fig 13. Package outline SOT23 (TO-236AB)

8. Revision history

Table 6. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
2N7002KA_2	20070925	Product data sheet		2N7002KA_1
Modifications:	• The Symbol graphic in Table 1 was updated.			
2N7002KA_1	20070605	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

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